



TEST REPORT

Test item description: Smart toilet

Trademark(s): N/A

Model/Type reference: 801, 502, 505, 703, 902, 905

Applicant's name: Guangdong Qixing Intelligent Sanitary Ware Co., LTD

Address: ROOM 301, 3RD FLOOR, NO. 18, NORTH SIDE OF DENG TANG PU INDUSTRIAL ZONE, GUYI VILLAGE, GUXIANG TOWN, CHAOAN DISTRICT, CHAOZHOU, GUANDONG, CHINA

Manufacturer: Guangdong Qixing Intelligent Sanitary Ware Co., LTD

Address: ROOM 301, 3RD FLOOR, NO. 18, NORTH SIDE OF DENG TANG PU INDUSTRIAL ZONE, GUYI VILLAGE, GUXIANG TOWN, CHAOAN DISTRICT, CHAOZHOU, GUANDONG, CHINA

Prepared By: Shenzhen CTB Testing Technology Co., Ltd.

Address: 1&2/F., Building A, No.26, Xinhe Road, Xinqiao, Xinqiao Street, Bao'an District, Shenzhen, Guangdong, China

Sample Received Date: Dec. 17, 2025

Sample tested Date: Dec. 17, 2025 to Jan. 20, 2026

Issue Date: Jan. 20, 2026

Report No.: CTB25121704701RE02

Test Standards: ETSI EN 301 489-1 V2.2.3 (2019-11)
ETSI EN 301 489-3 V2.3.2 (2023-01)

Test Results: PASS

Remark: This is RED EMC test report.

Compiled by: Reviewed by: Approved by:

Kai Chen

Kai Chen

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Bin Mei

Bin Mei / Director

Note: If there is any objection to the inspection results in this report, please submit a written report to the company within 15 days from the date of receiving the report. The test report is effective only with both signature and specialized stamp. This result(s) shown in this report refer only to the sample(s) tested. Without written approval of Shenzhen CTB Testing Technology Co., Ltd. this report can't be reproduced except in full. The tested sample(s) and the sample information are provided by the client. "*" indicates the testing items were fulfilled by subcontracted lab. "#" indicates the items are not in CNAS accreditation scope.

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(NOTE: N/A MEANS NOT APPLICABLE)

1. VERSION

Report No.	Issue Date	Description	Approved
CTB25121704701RE02	Jan. 20, 2026	Original	Valid

2. TEST SUMMARY

The Product has been tested according to the following specifications:

EMISSION		
Standard	Test Item	Test result
EN 55032	Conducted emissions from the AC mains power ports	Pass
EN 55032	Asymmetric mode conducted emissions	N/A ¹
EN 55032	Conducted differential voltage emissions	N/A ²
EN 55032	Radiated emissions	Pass
EN 61000-3-2	Harmonic current emission(H)	N/A ³
EN 61000-3-3	Voltage fluctuations & flicker(F)	Pass

IMMUNITY		
Standard	Test Item	Test result
IEC 61000-4-2	Electrostatic discharge (ESD)	Pass
IEC 61000-4-3	Continuous RF electromagnetic field disturbances(RS)	Pass
IEC 61000-4-4	Electrical fast transients/burst (EFT)	Pass
IEC 61000-4-5	Surges	Pass
IEC 61000-4-6	Radio frequency, common mode	Pass
IEC 61000-4-11	Voltage dips and interruptions (DIPS)	Pass

Remark:

1. Applicable to ports listed above and intended to connect to cables longer than 3 m.
2. The Product has no antenna port.
3. The Product belongs to Class A, and its power is less than 75W, so it deems to fulfil this standard without testing.

3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.

Test item	Value (dB)
Conducted Emission (150kHz-30MHz)	3.2
Radiated Emission(30MHz-1000MHz)	4.8
Radiated Emission(1GHz-6GHz)	4.9

4. PRODUCT INFORMATION AND TEST SETUP

4.1 Product Information

Model/Type reference:	801, 502, 505, 703, 902, 905
Model Difference:	All the model are the same circuit and RF module, only the model names are different. Test sample model: 801
SRD:	433.925MHz
Receiver Category:	2
Hardware Version:	V1.0
Software Version:	V1.0
Max. RF output power:	-2.535dBm
Type of Modulation:	ASK
Antenna installation:	Internal antenna
Ratings:	Toilet bowl: AC 220V~ 50Hz Remote control: DC 3.0V battery

4.2 Test Setup Configuration

See test photographs attached in EUT TEST SETUP PHOTOGRAPHS for the actual connections between Product and support equipment.

4.3 Support Equipment

Item	Equipment	Mfr/Brand	Model/Type No.	Series No.	Note

Notes:

1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

4.4 Test Mode

Test Mode	Description	Remark
Mode 1	SRD	TR, CR, TT, CT for EMS testing

NOTE: 1 The test modes were carried out for all operation modes. The final test mode of the EUT was the worst test mode for EMI, and its test data was showed.

2 “Link” is the connect horn alarm mode.

5. TEST FACILITY AND TEST INSTRUMENT USED

5.1 Test Facility

All measurement facilities used to collect the measurement data are located at 1&2F., Building A, No. 26, Xinhe Road, Xinqiao, Xinqiao Street, Bao'an District, Shenzhen, Guangdong, China. The site and apparatus are constructed in conformance with the requirements of ANSI C63.4 and CISPR 16-1-1 other equivalent standards.

5.2 Test Instrument Used

Continuous disturbance							
No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware version	Calibrated Date	Calibrated until
1	843 Shield Room	C/ R/ T	843	/	/	2024/6/22	2027/6/21
2	LISN	ROHDE&SCHWARZ	ESH3-Z5	831551852	/	2025/5/22	2026/5/21
3	EMI TEST RECEIVER	ROHDE&SCHWARZ	ESCI	100428	V4.42.SP3	2025/5/22	2026/5/21
4	Coaxial cable	ZDECL	Z302S	18091904	/	2025/5/22	2026/5/21
5	ISN	Schwarzbeck	NTFM8158	183	/	2025/6/18	2026/6/17
6	Voltage sensor	Schwarzbeck	TK 9420	01189	/	2025/9/19	2026/9/18
7	EZ-EMC	Frad	EMC-con3A1.1	/	/	/	/
8	Current Probe	FCC	F-52B	199453	/	2025/5/24	2026/5/23
9	Communication test set	R&S	CMW500	108058	B.19.07 (E1962B)	2025/5/23	2026/5/22
10	Communication test set	Agilent	E5515C	MY50102567	V3.5.80	2025/5/23	2026/5/22

Radiated emission(No.1 Chamber)							
No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware version	Calibrated until	Calibrated until
1	966 Chamber	C/ R/ T	966	/	/	2024/6/23	2027/6/22
2	Double Ridged Broadband Horn Antenna	Schwarzbeck	BBHA 9120 D	01911	/	2025/6/1	2026/5/31
3	TRILOG Broadband Antenna	Schwarzbeck	VULB 9168	00869	/	2025/6/29	2026/6/28
4	Amplifier	Agilent	8449B	3008A01838	/	2025/6/3	2026/6/2
5	Amplifier	HP	8447E	2945A02747	/	2025/5/23	2026/5/22
6	loop antenna	Schwarzbeck	FMZB 1519B	1519B-224	/	2025/6/2	2026/6/1
7	EMI TEST RECEIVER	ROHDE&SCHWARZ	ESPI	100362	RF_ATTEN_7 (104489/003)	2025/5/23	2026/5/22
8	Spectrum Analyzer	KEYSIGHT	N9020A	MY51289897	A.14.16	2025/5/23	2026/5/22
9	Coaxial cable	ETS	RFC-SNS-100-NMS-80	/	/	2025/5/24	2026/5/23

10	Coaxial cable	ETS	RFC-SN-100-NMS-20	/	/	2025/5/24	2026/5/23
11	Coaxial cable	ETS	RFC-SNS-100-SMS-20	/	/	2025/5/24	2026/5/23
12	Coaxial cable	ETS	RFC-NNS-100-NMS-300	/	/	2025/5/24	2026/5/23
13	EMI test software	Frad	EZ-EMC	Ver/ FA-03A2 RE	/	/	/
14	Communication test set	R&S	CMW500	108058	B.19.07 (E1962B)	2025/5/23	2026/5/22
15	Communication test set	Agilent	E5515C	MY50102567	V3.5.80	2025/5/23	2026/5/22

Harmonic current emission& Voltage changes, voltage fluctuations and flicker							
No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware Version	Calibrated Date	Calibrated until
1	Flicker & Harmonic Tester	Laplace Instruments	AC2000A	311363	Version 2.0	2025/5/30	2026/5/29
2	POWER SOURCE	HTEC Instruments	HPF5010	633088	/	2025/6/18	2026/6/17
3	H&F Test PC	HVAEIPC	S25	/	/	/	/
4	Flicker & Harmonic software	HTEC	Version 2.0	/	V2.0	/	/
5	Three-phase harmonic scintillation	Schloder	LMG 641	07552407	/	2025/6/18	2026/6/17
6	Three-phase harmonic power supply	CI	60kVA	/	/	2025/6/18	2026/6/17
7	Three-phase 75A impedance network	Yian	YIAN-3-75	375025	/	2025/6/18	2026/6/17
8	Harmonic flicker test system software GMC	GMC	LMG600 Control 3.130	/	LMG600 Control 3.130		/
9	Communication test set	R&S	CMW500	108058	Version 2.0	2025/5/23	2026/5/22
10	Communication test set	Agilent	E5515C	MY50102567	B.19.07 (E1962B)	2025/5/23	2026/5/22

Electrostatic discharges							
No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware Version	Calibrated Date	Calibrated until
1	ESD Simulator	TESTQ	NSG437	329	V01.00	2025/6/2	2026/6/1
2	Communication test set	R&S	CMW500	108058	Version 2.0	2025/5/23	2026/5/22
3	Communication test set	Agilent	E5515C	MY50102567	B.19.07 (E1962B)	2025/5/23	2026/5/22

Ringing Wave & Surges & Fast transients							
No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware Version	Calibrated Date	Calibrated until
1	Surge& Burst Generator	Lioncel	LSE-545CB	0180602	/	2025/5/21	2026/5/20
2	Capacitive coupling clamp	Lioncel	EFTC	018071801	/	2025/5/21	2026/5/20
3	Isolation transformer	Soulemc	HIT 90K	234915	/	/	/
4	Coupled decoupling network	Soulemc	SCDN SR200A	234909	/	2025/2/25	2026/2/24

5	Combinationsurge wave module	Soulemc	SCWG 10KP	234906	/	2025/2/25	2026/2/24
6	Communicationsurge wave module	Soulemc	STSG 10KP	234907	/	2025/2/25	2026/2/24
7	Ring wave module	Soulemc	SRWG 10KP	234908	/	2025/2/25	2026/2/24
8	surge computer	Soulemc	SCWG 10KP	234905	V0.1.0	/	/
9	Unshielded Symmetric Communication Line Coupling Network	Soulemc	SCN 8T	234910	/	2025/2/25	2026/2/24
10	Unshielded symmetrical communication line decoupling network	Soulemc	SDE 8T	234911	/	2025/2/25	2026/2/24
11	Capacitive coupling clamp	Soulemc	SCCC.4	234912	/	2025/2/25	2026/2/24
12	EFT Clamp SHVcable	Soulemc	50 欧 · 1.5M	/	/	/	/
13	Surge LAN cable	Soulemc	(8 线) 1M	/	/	/	/
14	Surge LAN cable	Soulemc	(8 线) 1.2M	/	/	/	/
15	EFT generator	Soulemc	SUCG 5000E	231903	V1.3.4	2025/2/25	2026/2/24
16	EFT Coupled decoupling network	Soulemc	SCDN E200A	234904	/	2025/2/25	2026/2/24
17	Communication test set	R&S	CMW500	108058	Version 2.0	2025/5/23	2026/5/22
18	Communication test set	Agilent	E5515C	MY50102567	B.19.07 (E1962B)	2025/5/23	2026/5/22

Voltage dips

No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware Version	Calibrated Date	Calibrated until
1	Voltage dip simulator	Lioncel	VDS-1102	180902	V1.04	2025/5/22	2026/5/21
2	DIPS fault simulator	Soulemc	SSAG 3P200T	234913	V1.5.4	2025/5/22	2026/5/21
3	Communication test set	R&S	CMW500	108058	Version 2.0	2025/5/23	2026/5/22
4	Communication test set	Agilent	E5515C	MY50102567	B.19.07 (E1962B)	2025/5/23	2026/5/22

Injected currents

No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware version	Calibrated Date	Calibrated until
1	C/S Test System	SKET	CITS-150K230M-75W	SK20210604	20H2	2025/6/18	2026/6/17
2	CDN	SKET	CDN-150K230M-M2/M3-16A	21302	/	2025/5/22	2026/5/21
3	CDN	Schaffner	CDNT400	/	/	2025/5/22	2026/5/21
4	6dB 100Watt Attenuator	SKET	AP-DC03G-100W-N-6dB	/	/	2025/5/28	2026/5/27
5	Electromagnetic Injection Clamp	Prima	PECL-100	/	/	2025/6/18	2026/6/17
6	50Ω Load	SKET	TL-DC01G-2W-50 BNC	/	/	2025/6/18	2026/6/17
7	CS test software	SKET	EMC-S	V2.0.0.11	/	/	/

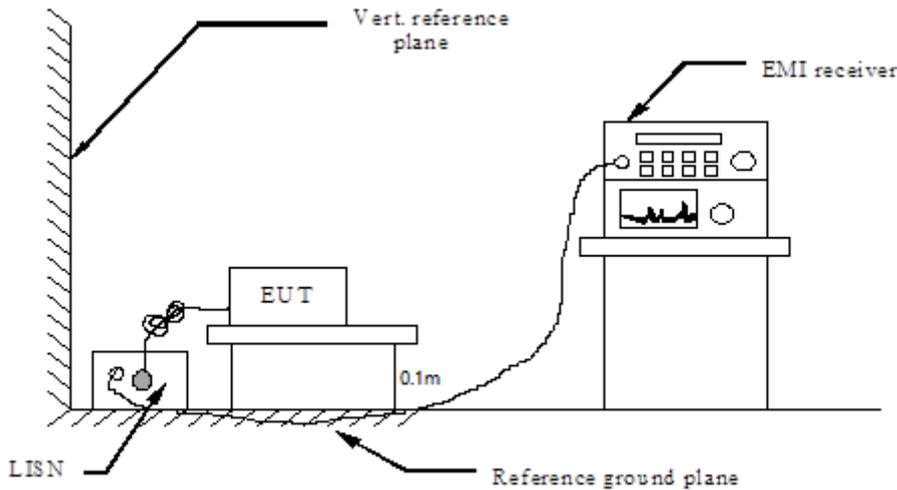
8	M5 Coupled decoupling network	HTEC	CDN M5	234902	/	2025/6/3	2026/6/2
9	M2 Coupled decoupling network	HTEC	CDN M2	234901	/	2025/6/3	2026/6/2
10	Communication test set	R&S	CMW500	108058	Version 2.0	2025/5/23	2026/5/22
11	Communication test set	Agilent	E5515C	MY5010256 7	B.19.07 (E1962B)	2025/5/23	2026/5/22

Radio frequency electromagnetic field

No.	Equipment	Manufacturer	Type No.	Serial No.	Firmware Version	Calibrated Date	Calibrated until
1	966 Chamber	C/ R/ T	966	/	/	2024/6/23	2027/6/22
2	Signal Generator	Agilent	N5181A	MY4906092 0	A.01.60	2025/5/22	2026/5/21
3	Stacked Double Log.-Per. Antenna	SKET	STLP 9129 Plus	2106070106	/	/	/
4	Switch Controller	SKET	RFSU-DC18G-4C	2106070105	/	/	/
5	RF Power Meter	Agilent	E9304A	MY4149046 2	/	2025/5/23	2026/5/22
6	RF Power Meter	Agilent	E9301A	MY4149567 5	/	2025/5/23	2026/5/22
7	E-Field Probe	Narda	EP-601	811ZX10305	/	2025/6/3	2026/6/2
8	Power Amplifier	SKET	HAP-80M01G-250 W	2106070103	/	2025/5/30	2026/5/29
9	Power Amplifier	SKET	HAP-01G 06G-75W	2106070104	/	2025/5/30	2026/5/29
10	Audio Analysis	R&S	ATS-1	ATS 1-41152	/	2025/5/23	2026/5/22
11	Audio Output Matching Network	SKET	RCO Network	/	/	2025/5/23	2026/5/22
12	RS test software	SKET	V2.0.0.19	/	/	/	/
13	Communication test set	R&S	CMW500	108058	Version 2.0	2025/5/23	2026/5/22
14	Communication test set	Agilent	E5515C	MY5010256 7	B.19.07 (E1962B)	2025/5/23	2026/5/22

6. CONDUCTED EMISSIONS

6.1 Block Diagram Of Test Setup



6.2 Limit

Limits for Conducted emissions at the mains ports of Class B MME

Frequency range (MHz)	Limits dB(μV)	
	Quasi-peak	Average
0,15 to 0,50	66 to 56*	56 to 46*
0,50 to 5	56	46
5 to 30	60	50

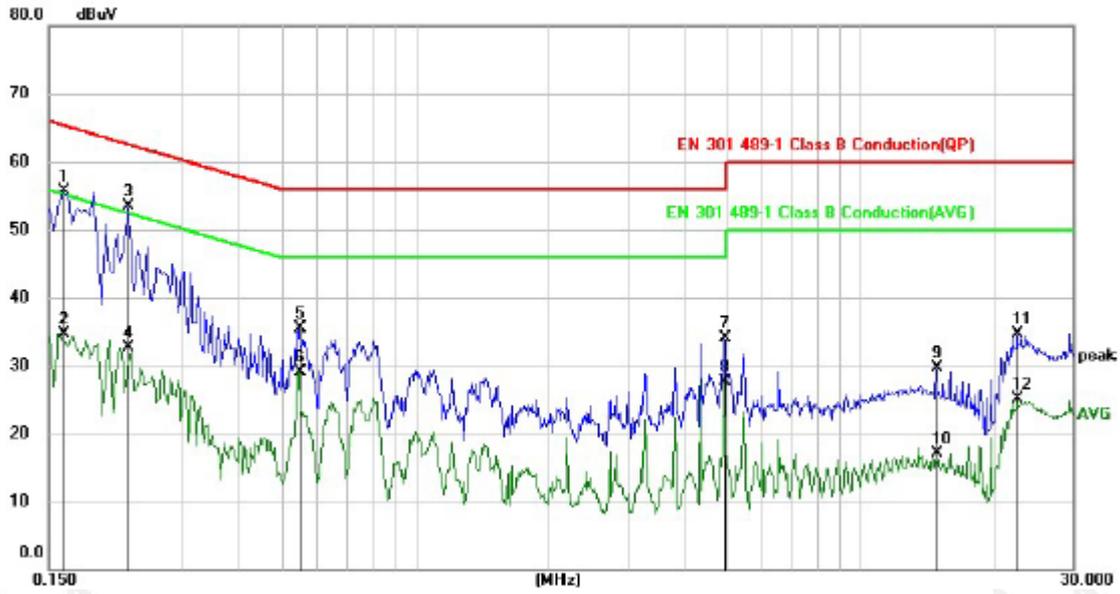
Notes: 1. *Decreasing linearly with logarithm of frequency.
2. The lower limit shall apply at the transition frequencies.

6.3 Test procedure

- The Product was placed on a nonconductive table 0.1m above the horizontal ground reference plane, and 0.4 m from the vertical ground reference plane, and connected to the main through Line Impedance Stability Network (L.I.S.N).
- The RBW of the receiver was set at 9 kHz in 150 kHz ~30MHz with Peak and AVG detector in Max Hold mode. Run the receiver's pre-scan to record the maximum disturbance generated from Product in all power lines in the full band.
- For each frequency whose maximum record was higher or close to limit, measure its QP and AVG values and record.

6.4 Test Result

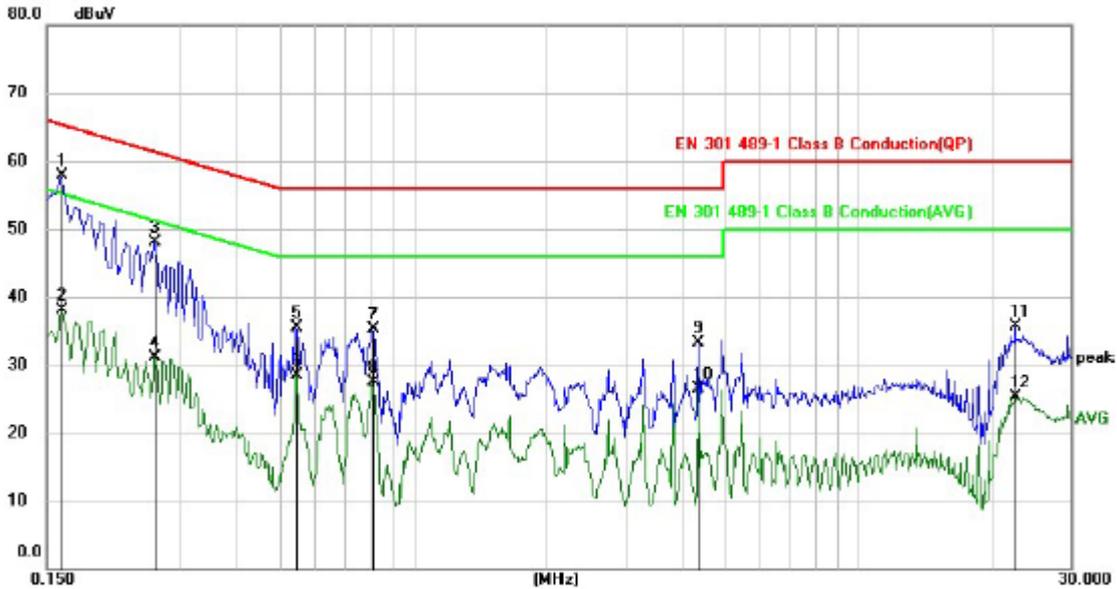
Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Phase :	L
Test Mode	1	Remark:	N/A



No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV	Limit dBuV	Over dB	Detector
1		0.1620	45.58	10.07	55.65	65.36	-9.71	QP
2		0.1620	24.59	10.07	34.66	55.36	-20.70	AVG
3	*	0.2260	43.34	10.08	53.42	62.60	-9.18	QP
4		0.2260	22.54	10.08	32.62	52.60	-19.98	AVG
5		0.5500	25.46	10.09	35.55	56.00	-20.45	QP
6		0.5500	18.97	10.09	29.06	46.00	-16.94	AVG
7		4.9300	23.91	10.28	34.19	56.00	-21.81	QP
8		4.9300	17.36	10.28	27.64	46.00	-18.36	AVG
9		14.7900	19.01	10.72	29.73	60.00	-30.27	QP
10		14.7900	6.32	10.72	17.04	50.00	-32.96	AVG
11		22.4580	23.68	11.08	34.76	60.00	-25.24	QP
12		22.4580	13.95	11.08	25.03	50.00	-24.97	AVG

Remark: Result=Reading +Factor
Over Limit=Result -Limit

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Phase :	N
Test Mode	1	Remark:	N/A

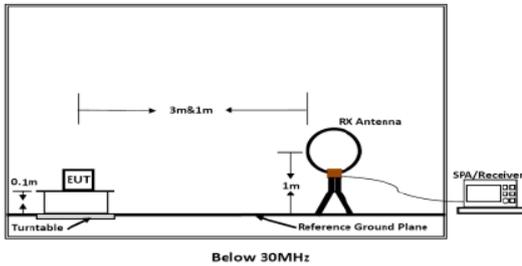


No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV	Limit dBuV	Over dB	Detector
1	*	0.1620	47.78	10.07	57.85	65.36	-7.51	QP
2		0.1620	28.02	10.07	38.09	55.36	-17.27	AVG
3		0.2620	38.12	10.08	48.20	61.37	-13.17	QP
4		0.2620	20.99	10.08	31.07	51.37	-20.30	AVG
5		0.5460	25.46	10.09	35.55	56.00	-20.45	QP
6		0.5460	18.35	10.09	28.44	46.00	-17.56	AVG
7		0.8100	25.10	10.12	35.22	56.00	-20.78	QP
8		0.8100	17.39	10.12	27.51	46.00	-18.49	AVG
9		4.3820	23.10	10.26	33.36	56.00	-22.64	QP
10		4.3820	16.34	10.26	26.60	46.00	-19.40	AVG
11		22.4619	24.56	11.08	35.64	60.00	-24.36	QP
12		22.4619	14.23	11.08	25.31	50.00	-24.69	AVG

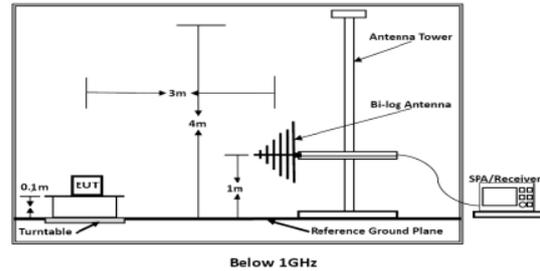
Remark: Result=Reading +Factor
Over Limit=Result -Limit

7. RADIATEMISSIONS TEST

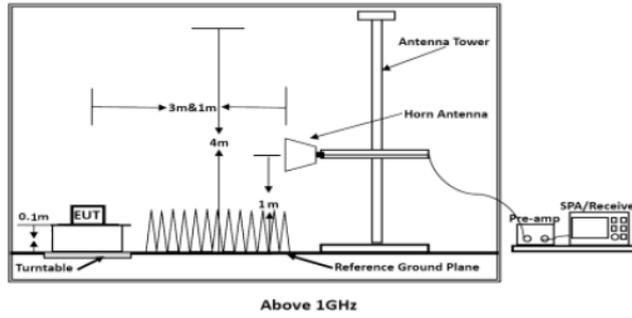
7.1 Block Diagram Of Test Setup



Below 30MHz
Figure 1. Below 30MHz



Below 1GHz
Figure 2. 30MHz to 1GHz



Above 1GHz
Figure 3. Above 1GHz

7.2 Limits

Limits for radiated disturbance of Class B MME

Frequency (MHz)	Quasi-peak limits at 3m dB(μV/m)
30-230	40
230-1000	47

Frequency (GHz)	limit above 1G at 3m dB(μV/m)	
	Average	peak
1-3	50	70
3-6	54	74

Note: The lower limit shall apply at the transition frequencies.

7.3 Test Procedure

30MHz ~ 1GHz:

- a. The Product was placed on the nonconductive turntable 0.1m above the ground in a semi anechoic chamber.
- b. Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 120 kHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied between 1~4 m in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- c. For each frequency whose maximum record was higher or close to limit, measure its QP value: vary the antenna's height and rotate the turntable from 0 to 360 degrees to find the height and degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to QP Detector and specified bandwidth with Maximum Hold Mode, and record the maximum value.

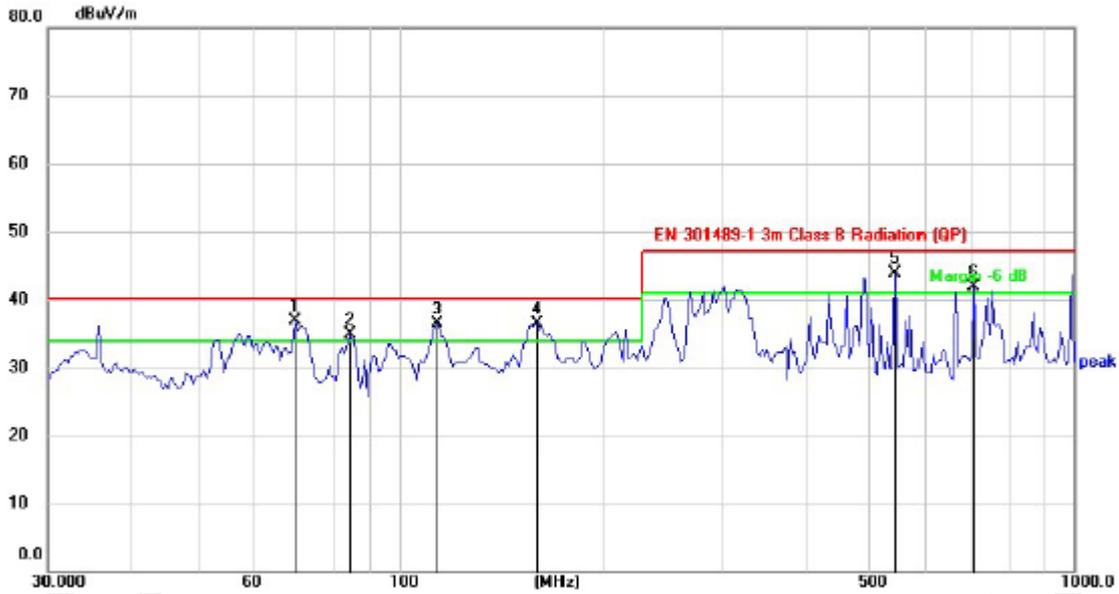
Above 1GHz:

- a. The Product was placed on the non-conductive turntable 0.8m above the ground in a full anechoic chamber..
- b. Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 1MHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- c. For each frequency whose maximum record was higher or close to limit, measure its AV value: rotate the turntable from 0 to 360 degrees to find the degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to AV value and specified bandwidth with Maximum Hold Mode, and record the maximum value.

7.4 Test Results

Below 1GHz

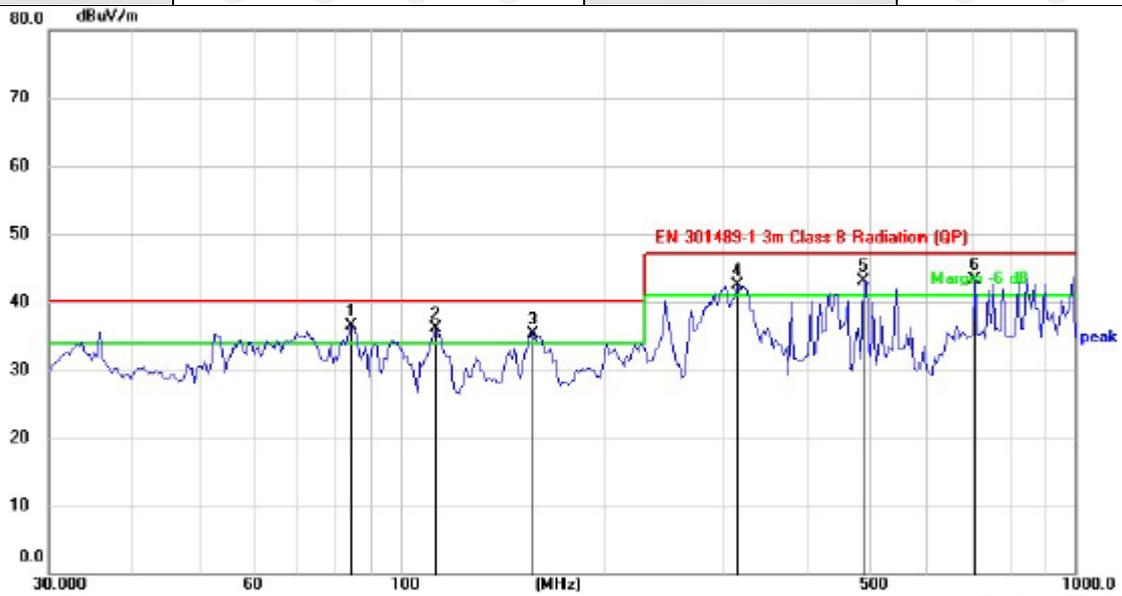
Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Polarization :	Horizontal
Test Mode	1	Remark:	N/A



No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV/m	Limit dB/m	Over dB	Detector
1	*	70.2132	44.76	-7.79	36.97	40.00	-3.03	QP
2	!	84.4054	43.40	-8.49	34.91	40.00	-5.09	QP
3	!	113.7142	42.90	-6.46	36.44	40.00	-3.56	QP
4	!	160.0646	39.85	-3.43	36.42	40.00	-3.58	QP
5	!	546.1390	41.47	2.35	43.82	47.00	-3.18	QP
6	!	710.4266	35.22	6.61	41.83	47.00	-5.17	QP

Remark: Result=Reading +Factor
Over Limit=Result -Limit

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Polarization :	Vertical
Test Mode	1	Remark:	N/A



No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV/m	Limit dB/m	Over dB	Detector
1	*	84.4054	44.90	-8.49	36.41	40.00	-3.59	QP
2	!	112.7218	42.68	-6.55	36.13	40.00	-3.87	QP
3	!	157.2828	39.02	-3.69	35.33	40.00	-4.67	QP
4	!	317.1444	44.65	-2.24	42.41	47.00	-4.59	QP
5	!	487.3149	42.35	0.71	43.06	47.00	-3.94	QP
6	!	710.4266	36.72	6.61	43.33	47.00	-3.67	QP

Remark: Result=Reading +Factor
Over Limit=Result -Limit

Above 1GHz

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Polarization :	Horizontal
Test Mode	1	Remark:	N/A

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Det.
1	1967.46	46.72	1.49	48.21	70.00	-21.79	peak
2	1965.89	27.84	1.49	29.32	50.00	-20.68	AVG
3	3773.00	42.97	5.78	48.75	74.00	-25.25	peak
4	3775.57	25.46	5.78	31.24	54.00	-22.76	AVG
5	4839.31	41.56	9.54	51.11	74.00	-22.89	peak
6	4843.52	24.77	9.54	34.31	54.00	-19.69	AVG

Remark: Result=Reading +Factor
Over Limit=Result -Limit

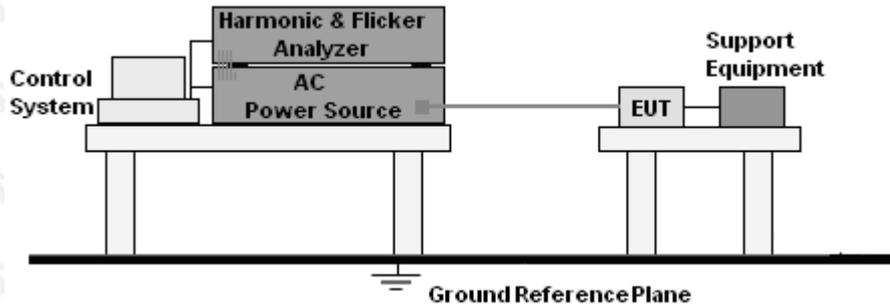
Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Polarization :	Vertical
Test Mode	1	Remark:	N/A

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Det.
1	1998.21	46.86	1.51	48.37	70.00	-21.63	peak
2	1997.32	28.73	1.51	30.24	50.00	-19.76	AVG
3	3810.50	45.57	5.92	51.49	74.00	-22.51	peak
4	3810.31	29.32	5.92	35.24	54.00	-18.76	AVG
5	4771.55	44.02	9.32	53.34	74.00	-20.66	peak
6	4771.88	26.19	9.32	35.51	54.00	-18.49	AVG

Remark: Result=Reading +Factor
Over Limit=Result -Limit

8. HARMONIC CURRENT EMISSION(H)

8.1 Block Diagram of Test Setup



8.2 Limit

EN IEC 61000-3-2:2019 Clause 7.

8.3 Test Procedure

- a. The Product was placed on the top of a non-conductive table above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- b. The correspondent test program of test instrument to measure the current harmonics emanated from Product was chosen. The measure time shall be not less than the time necessary for the Product to be exercised.

8.4 Test Results

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Test Mode	1
Remark:	N/A	Test results	PASS

Describe:

 Test Result: **Pass** Source qualification(Power Off Load): **Idle - Pass**

THC(mA): 90.400 I - THD(%): 14.9 POHC(mA):45.800 POHC Limit(mA):251.353

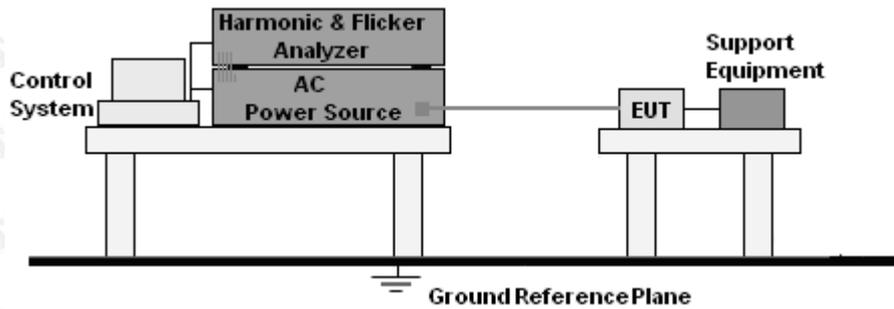
Parameter values during test:

V_RMS (Volts): 231.2	Frequency(Hz): 50.0
I_RMS(mA): 636.2	Crest Factor: 3.740
Power (Watts): 120.9	Power Factor: 0.753

Harm#	Harms(filtered) (mA)	Limit (mA)	Harms(avg) (mA)	100%Limit	Harms(max) (mA)	150%Limit	Status
I_Fund	607.400						
2	14.200	1080.000	185.400	17.167	205.200	12.667	Pass
3	29.200	2300.000	56.200	2.443	63.200	1.832	Pass
4	3.000	430.000	37.500	8.721	45.100	6.992	Pass
5	27.700	1140.000	39.100	3.430	42.500	2.485	Pass
6	1.400	300.000	15.700	5.233	19.400	4.311	Pass
7	29.700	770.000	36.700	4.766	37.900	3.281	Pass
8	1.300	230.000	13.000	5.652	15.800	4.580	Pass
9	28.100	400.000	34.200	8.550	35.500	5.917	Pass
10	0.900	184.000	9.300	5.054	12.200	4.420	Pass
11	26.300	330.000	31.900	9.667	33.100	6.687	Pass
12	0.900	153.300	8.400	5.479	10.900	4.740	Pass
13	25.800	210.000	30.700	14.619	31.300	9.937	Pass
14	1.000	131.400	7.800	5.936	9.600	4.871	Pass
15	24.700	150.000	28.900	19.267	29.500	13.111	Pass
16	0.800	115.000	5.900	5.130	7.500	4.348	Pass
17	22.500	132.400	26.300	19.864	26.900	13.545	Pass
18	0.900	102.200	6.300	6.164	7.500	4.892	Pass
19	21.300	118.400	24.600	20.777	25.100	14.133	Pass
20	0.800	92.000	4.800	5.217	5.700	4.130	Pass
21	19.800	107.100	22.500	21.008	23.000	14.317	Pass
22	0.800	83.600	6.000	7.177	7.100	5.662	Pass
23	17.800	97.800	20.000	20.450	20.500	13.974	Pass
24	0.800	76.700	5.000	6.519	6.200	5.389	Pass
25	16.000	90.000	17.700	19.667	18.100	13.407	Pass
26	0.800	70.800	5.700	8.051	6.900	6.497	Pass
27	14.500	83.300	15.800	18.968	16.000	12.805	Pass
28	0.700	65.700	4.500	6.849	5.600	5.682	Pass
29	12.700	77.600	13.500	17.397	13.800	11.856	Pass
30	0.700	61.300	4.600	7.504	5.500	5.982	Pass
31	10.900	72.600	11.500	15.840	11.700	10.744	Pass
32	0.600	57.500	3.500	6.087	4.100	4.754	Pass
33	9.500	68.200	9.800	14.370	10.000	9.775	Pass
34	0.600	54.100	3.500	6.470	4.200	5.176	Pass
35	8.000	64.300	8.000	12.442	8.300	8.605	Pass
36	0.500	51.100	3.200	6.262	3.800	4.958	Pass
37	6.500	60.800	6.300	10.362	6.700	7.346	Pass
38	0.500	48.400	3.100	6.405	3.900	5.372	Pass
39	5.300	57.700	5.000	8.666	5.300	6.124	Pass
40	0.400	46.000	3.000	6.522	3.700	5.362	Pass

9. VOLTAGE FLUCTUATIONS & FLICKER(F)

9.1 Block Diagram of Test Setup



9.2 Limit

EN 61000-3-3:2013/A1:2019 Clause 5.

9.3 Test Procedure

- a. The Product was placed on the top of a non-conductive table above the ground and operated to produce the most unfavorable sequence of voltage changes under normal operating conditions.
- b. During the flick test, the measure time shall include that part of whole operation cycle in which the Product produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

9.4 Test Results

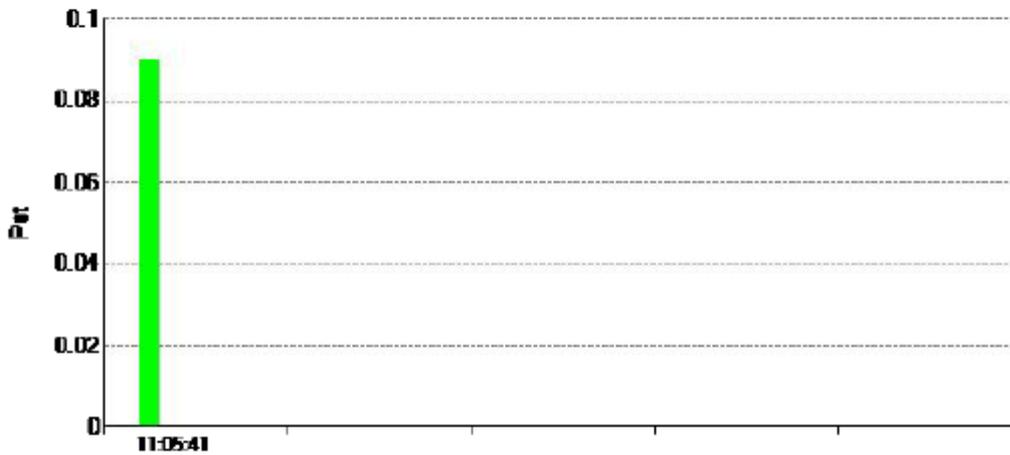
Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Test Mode	1
Remark:	N/A	Test results	PASS

Describe:

Load Power : 0.017 kW **Power Factor:**0.630
Load Current : 0.097 Arms **Crest Factor:**2.289
Nominal Voltage : 231.34 Vrms

Test Result: Pass **Status:** Test Completed

Pst_i and limit line European Limits



Result:

T-max (ms):	0.00	Test limit (ms):	500.00	Pass
Highest dc (%):	0.15	Test limit (%):	3.30	Pass
Highest dmax (%):	0.12	Test limit (%):	4.00	Pass
Highest Pst (10 min. period):	0.09	Test limit:	1.00	Pass

10. IMMUNITY TEST OF GENERAL THE PERFORMANCE CRITERIA

Product Standard	ETSI EN 301 489-1
	<p>The performance criteria are used to take a decision on whether a radio equipment passes or fails immunity tests.</p> <p>For the purpose of the present document two categories of performance criteria apply:</p> <ul style="list-style-type: none"> •Performance criteria for continuous phenomena. •Performance criteria for transient phenomena. <p>NOTE: Normally, the performance criteria depends upon the type of radio equipment and/or its intended application. Thus, the present document only contains general performance criteria commonly used for the assessment of radio equipment.</p>
<p>Performance criteria for continuous phenomena</p>	<p>During the test, the equipment shall:</p> <ul style="list-style-type: none"> •continue to operate as intended; •not unintentionally transmit; •not unintentionally change its operating state; •not unintentionally change critical stored data.
<p>Performance criteria for transient phenomena</p>	<p>For all ports and transient phenomena with the exception described below, the following applies:</p> <ul style="list-style-type: none"> •The application of the transient phenomena shall not result in a change of the mode of operation (e.g. unintended transmission) or the loss of critical stored data. •After application of the transient phenomena, the equipment shall operate as intended. <p>For surges applied to symmetrically operated wired network ports intended to be connected directly to outdoor lines the following criteria applies:</p> <ul style="list-style-type: none"> •For products with only one symmetrical port intended for connection to outdoor lines, loss of function is allowed, provided the function is self-recoverable, or can be otherwise restored. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost. •For products with more than one symmetrical port intended for connection to outdoor lines, loss of function on the port under test is allowed, provided the function is self-recoverable. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

According To EN 301489 -3 standard, The General Performance Criteria As Following:

Table 1: Performance criteria

Criteria	During the test	After test (i.e. as a result of the application of the test)
A	Operate as intended No loss of function No unintentional responses	Operate as intended No loss of function No degradation of performance No loss of stored data or user programmable functions
B	May show loss of function No unintentional responses	Operate as intended Lost function(s) shall be self-recoverable No degradation of performance No loss of stored data or user programmable functions
NOTE: Whether a phenomenon is considered transient, continuous or otherwise is indicated in the test procedures for the phenomenon in ETSI EN 301 489-1 [1], clause 9.		

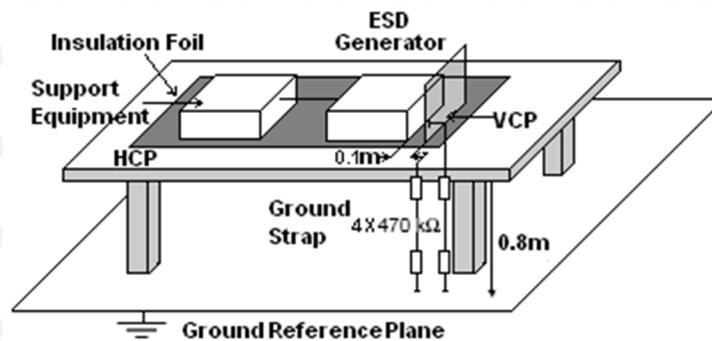
- performance criterion A applies for immunity tests with phenomena of a continuous nature;
- performance criterion B applies for immunity tests with phenomena of a transient nature.

11. ELECTROSTATIC DISCHARGE (ESD)

11.1 Test Specification

Test Port	: Enclosure port
Discharge Impedance	: 330 ohm / 150 pF
Discharge Mode	: Single Discharge
Discharge Period	: one second between each discharge

11.2 Block Diagram of Test Setup



11.3 Test Procedure

- Electrostatic discharges were applied only to those points and surfaces of the Product that are accessible to users during normal operation.
- The test was performed with at least ten single discharges on the pre-selected points in the most sensitive polarity.
- The time interval between two successive single discharges was at least 1 second.
- The ESD generator was held perpendicularly to the surface to which the discharge was applied and the return cable was at least 0.2 meters from the Product.
- Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.
- Air discharges were applied with the round discharge tip of the discharge electrode approaching the Product as fast as possible (without causing mechanical damage) to touch the Product. After each discharge, the ESD generator was removed from the Product and re-triggered for a new single discharge. The test was repeated until all discharges were complete.
- At least ten single discharges (in the most sensitive polarity) were applied to the Horizontal Coupling Plane at points on each side of the Product. The ESD generator was positioned vertically at a distance of 0.1 meters from the Product with the discharge electrode touching the HCP.
- At least ten single discharges (in the most sensitive polarity) were applied to the center of one vertical edge of the Vertical Coupling Plane in sufficiently different positions that the four faces of the Product were completely illuminated. The VCP (dimensions 0.5m x 0.5m) was placed vertically to and 0.1 meters from the Product.

11.4 Test Results

Temperature :	23°C	Relative Humidity :	54%
Pressure :	101kPa	Test Mode :	Mode1

Discharge Method	Discharge Position	Voltage (±kV)	Min. No. of Discharge per polarity (Each Point)	Performance Criterion
Contact Discharge	Conductive Surfaces	4	10	A
	Indirect Discharge HCP	4	10	A
	Indirect Discharge VCP	4	10	A
Air Discharge	Slots, Apertures, and Insulating Surfaces	8	10	A

Note: A: No performance degradation during test.

B: During the test, the EUT shut down, after the test, it reset by itself.

C: During the test, the EUT shut down, after the test, it reset by user.

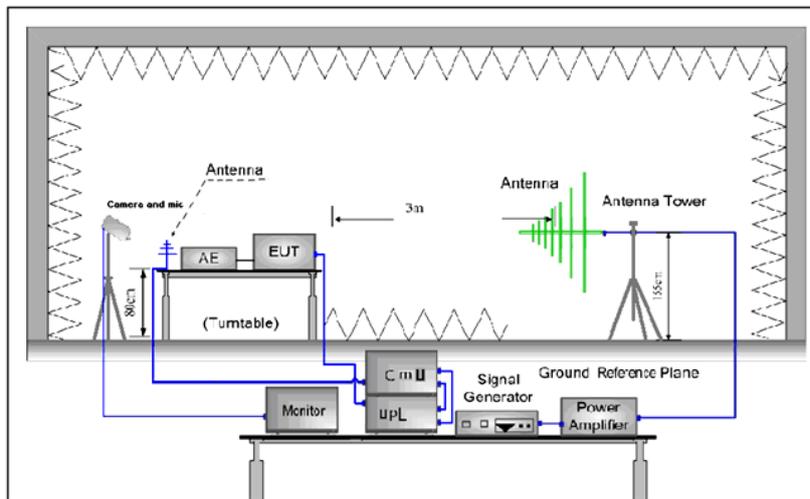
12. CONTINUOUS RF ELECTROMAGNETIC FIELD DISTURBANCES(RS)

12.1 Test Specification

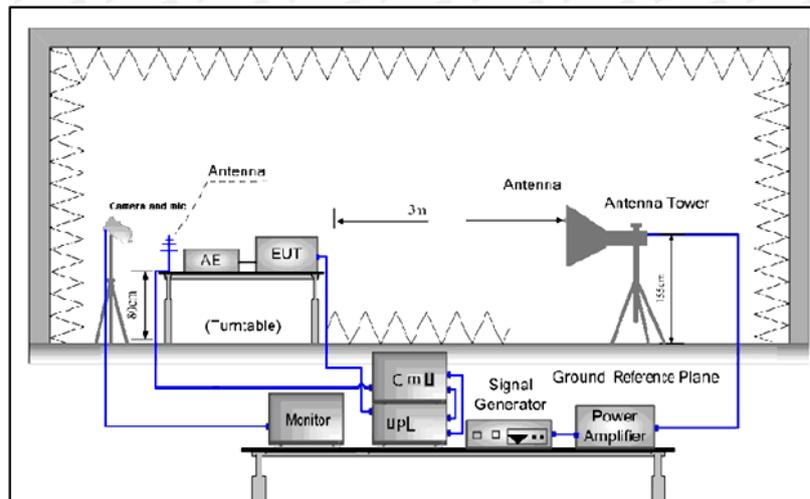
Test Port	: Enclosure port
Step Size	: 1%
Modulation	: 1kHz, 80% AM
Dwell Time	: 1 second
Polarization	: Horizontal & Vertical

12.2 Block Diagram of Test Setup

Below 1GHz:



Above 1GHz:



12.3 Test Procedure

- a. The testing was performed in a fully-anechoic chamber. The transmit antenna was located at a distance of 3 meters from the Product.
- b. The frequency range is swept from 80MHz to 6000MHz, with the signal 80% amplitude modulated with a 1 kHz sine wave, and the step size was 1%.
- c. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond, but should not exceed 5 s at each of the frequencies during the scan.
- d. The test was performed with the Product exposed to both vertically and horizontally polarized fields on each of the four sides.
- e. For Broadcast reception function: Group 2 not apply in this test.

12.4 Test Results

Temperature :	23 °C	Relative Humidity :	54%
Pressure :	101kPa	Test Mode :	Mode1

Frequency	Position	Field Strength	Performance Criterion
80 - 6000MHz	Front, Right, Back, Left, Up, Down	3V/m	A

Note: A: No performance degradation during test.

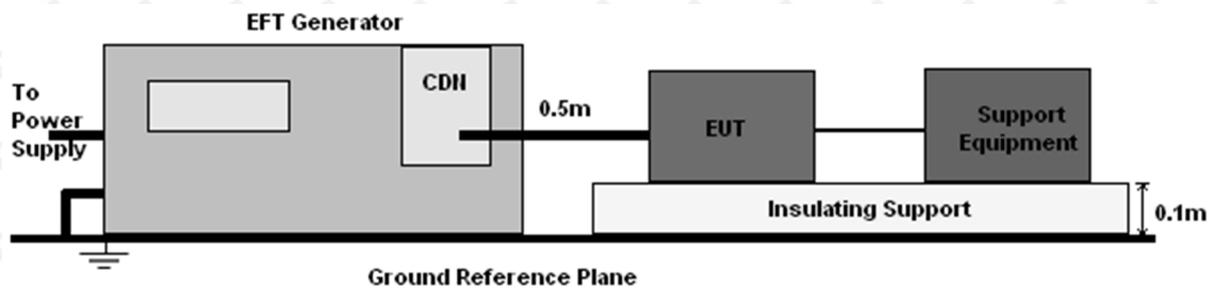
13. ELECTRICAL FAST TRANSIENTS/BURST (EFT)

13.1 Test Specification

Test Port	:	input a.c. power port
Impulse Frequency	:	5 kHz
Impulse Wave-shape	:	5/50 ns
Burst Duration	:	15 ms
Burst Period	:	300 ms
Test Duration	:	2 minutes per polarity

13.2 Block Diagram of EUT Test Setup

For input a.c.power port:



13.3 Test Procedure

- The Product and support units were located on a non-conductive table above ground reference plane.
- A 0.5m-long power cord was attached to Product during the test.

13.4 Test Results

Temperature :	23 °C	Relative Humidity :	54%
Pressure :	101kPa	Test Mode :	Mode1

Coupling	Voltage (kV)	Polarity	Performance Criterion
AC Mains L-N	1.0	±	A
Signal Line	0.5	±	N/A
LAN Ports	0.5	±	N/A
DC Ports	0.5	±	N/A

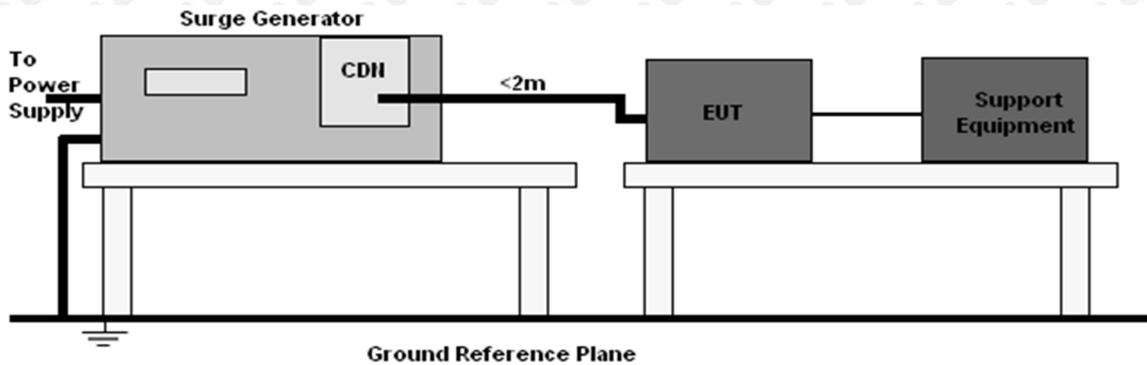
Note: A: No performance degradation during test.
 B: During the test, the EUT shut down, after the test, it reset by itself.
 C: During the test, the EUT shut down, after the test, it reset by user.

14. SURGES IMMUNITY TEST

14.1 Test Specification

Test Port	: input a.c. power port
Wave-Shape	: Open Circuit Voltage - 1.2 / 50 us Short Circuit Current - 8 / 20 us
Pulse Repetition Rate	: 1 pulse / min.
Phase Angle	: 0° / 90° / 180° / 270°
Test Events	: 5 pulses (positive & negative) for each polarity

14.2 Block Diagram of EUT Test Setup



14.3 Test Procedure

- a. The surge is to be applied to the Product power supply terminals via the capacitive coupling network. Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines, and to provide sufficient decoupling impedance to the surge wave.
- b. The power cord between the Product and the coupling/decoupling networks shall be 2 meters in length (or shorter). Interconnection line between the Product and the coupling/decoupling networks shall be 2 meters in length (or shorter).

14.4 Test Result

Temperature :	23 °C	Relative Humidity :	54%
Pressure :	101kPa	Test Mode :	Mode1

Coupling Line	Voltage (kV)	Polarity	Performance Criterion
L - N	1	±	A
L - PE	2	±	N/A
N - PE	2	±	N/A
LAN Ports	±1	/	N/A

Note: A: No performance degradation during test.
 B: During the test, the EUT shut down, after the test, it reset by itself.
 C: During the test, the EUT shut down, after the test, it reset by user.

Remark: No test shall be required where normal functioning cannot be achieved because of the impact of the CDN on the Product.

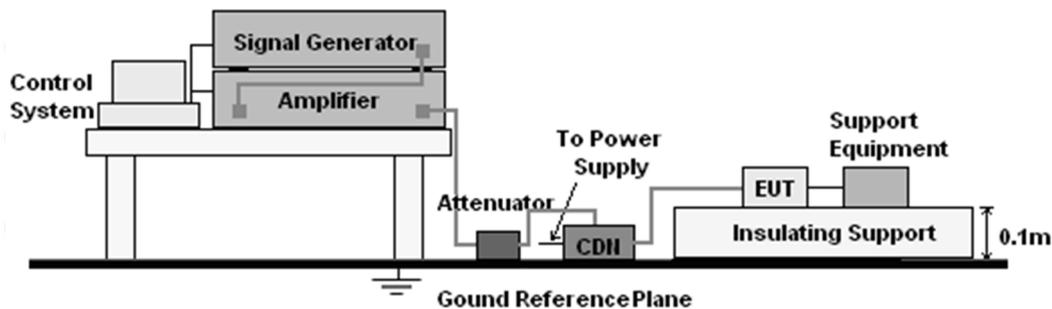
15. CONTINUOUS INDUCED RF DISTURBANCES (CS)

15.1 Test Specification

Test Port	: input a.c.power port
Step Size	: 1%
Modulation	: 1kHz, 80% AM
Dwell Time	: 1 second

15.2 Block Diagram of EUT Test Setup

For input a.c. power port:



15.3 Test Procedure

For input a.c.power port:

- The Product and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- The frequency range is swept from 150 kHz to 10MHz, 10MHz to 30MHz, 30MHz to 80MHz with the signal 80% amplitude modulated with a 1 kHz sine wave, and the step size was 1% of fundamental.
- The dwell time at each frequency shall be not less than the time necessary for the Product to be able to respond.

15.4 Test Result

Temperature :	23 °C	Relative Humidity :	54%
Pressure :	101kPa	Test Mode :	Mode1

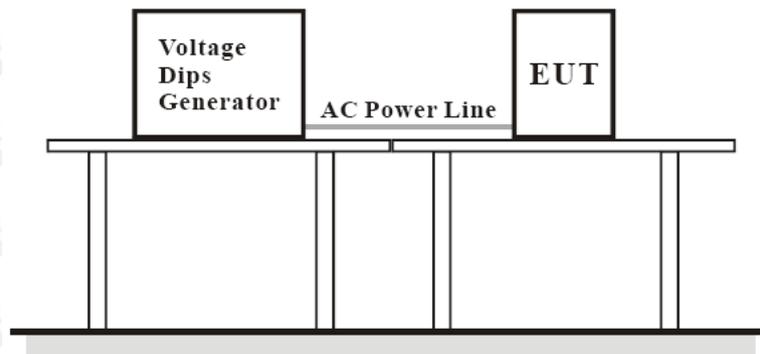
Inject Line	Frequency (MHz)	Voltage Level (V r.m.s.)	Performance Criterion
ac. port	0.15 - 80	3	A
LAN Ports	0.15 - 80	3	N/A
Note: A: No performance degradation during test.			

16. VOLTAGE DIPS AND INTERRUPTIONS (DIPS)

16.1 Test Specification

Test Port	:	input a.c. power port
Phase Angle	:	0°, 180°
Test cycle	:	3 times

16.2 Block Diagram of EUT Test Setup



16.3 Test Procedure

- The Product and support units were located on a non-conductive table above ground floor.
- Set the parameter of tests and then perform the test software of test simulator.
- Conditions changes to occur at 0 degree crossover point of the voltage waveform.

16.4 Test Result

Temperature :	23 °C	Relative Humidity :	54%
Pressure :	101kPa	Test Mode :	Mode1

Voltage Dips:			
Test Level % U_T	Voltage dips in % U_T	Duration (ms)	Performance Criterion
0	100	10	A
0	100	20	A
70	30	500	A
Voltage Interruptions:			
0	100	5000	C
Note: A: No performance degradation during test. B: During the test, the EUT shut down, after the test, it reset by itself. C: During the test, the EUT shut down, after the test, it reset by user.			

17. EUT PHOTOGRAPHS

External Photos EUT Photo 1



EUT Photo 2



EUT Photo 3



EUT Photo 4



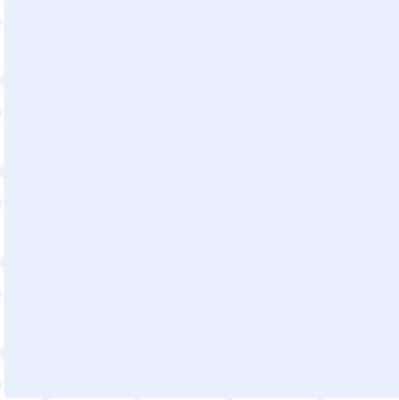
EUT Photo 5



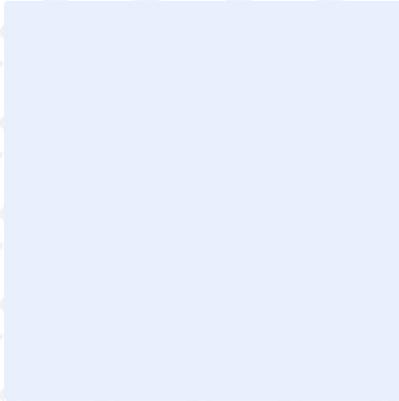
EUT Photo 6



EUT Photo 7



EUT Photo 8



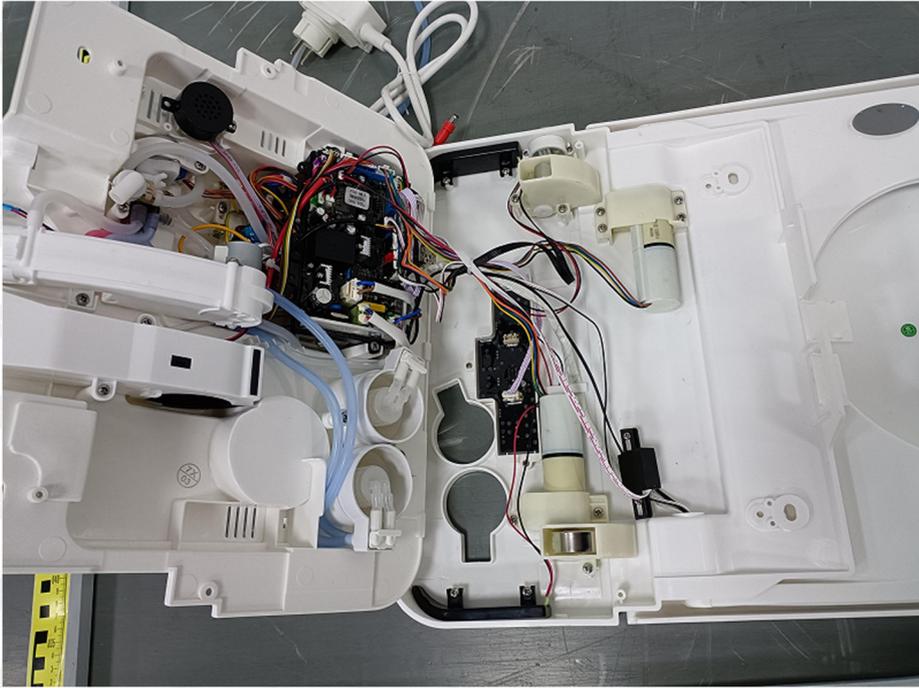
Internal Photos
EUT Photo 1



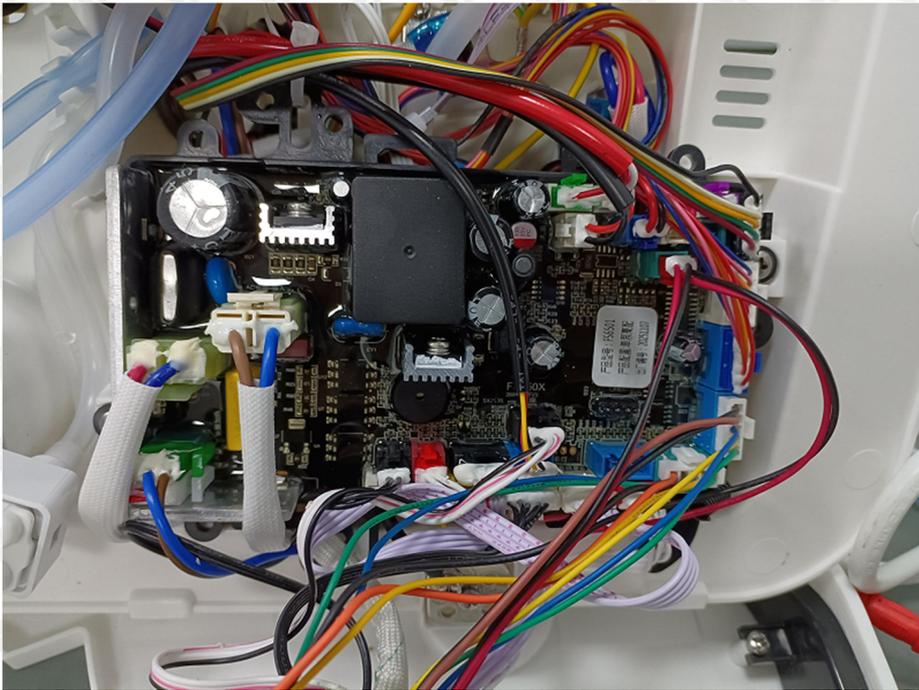
EUT Photo 2



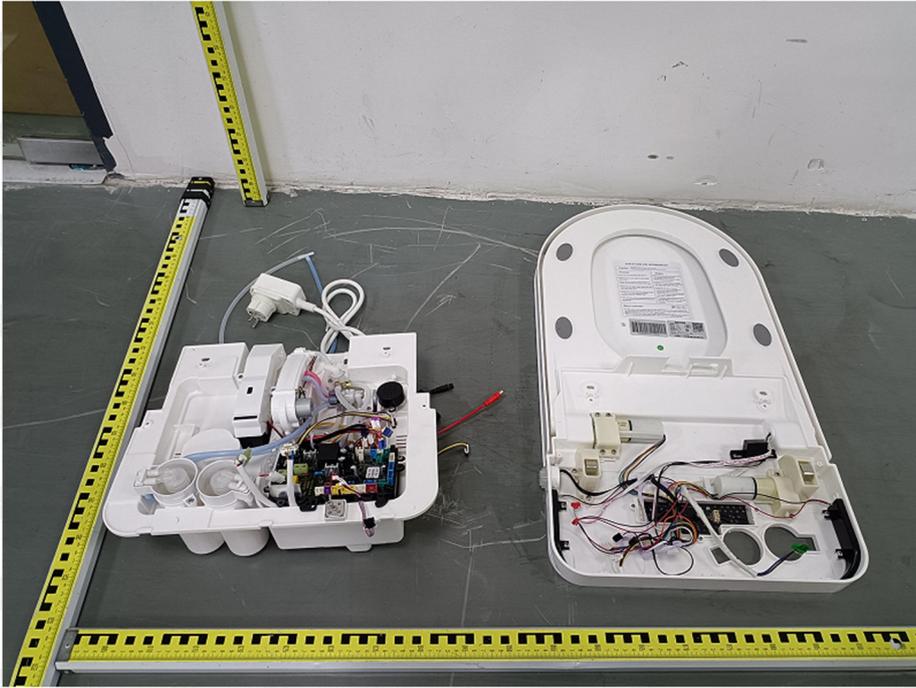
EUT Photo 3



EUT Photo 4



EUT Photo 5



EUT Photo 6



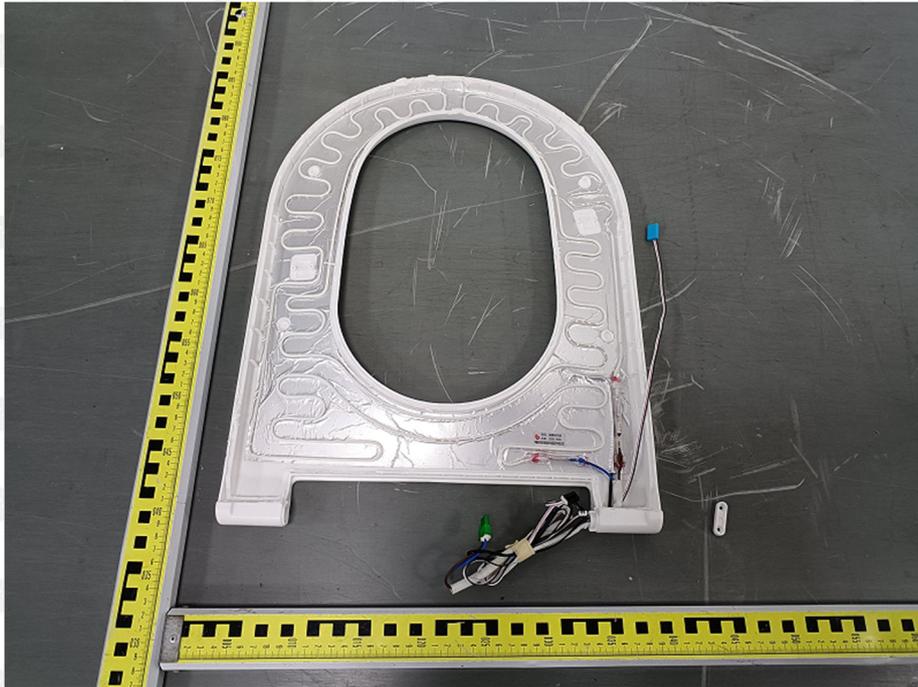
EUT Photo 7



EUT Photo 8



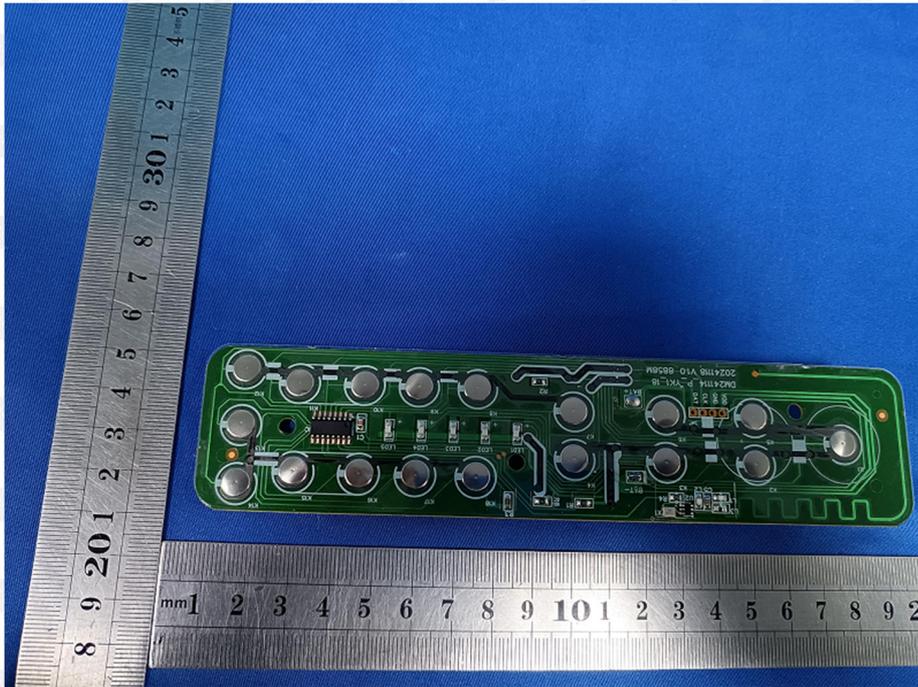
EUT Photo 9



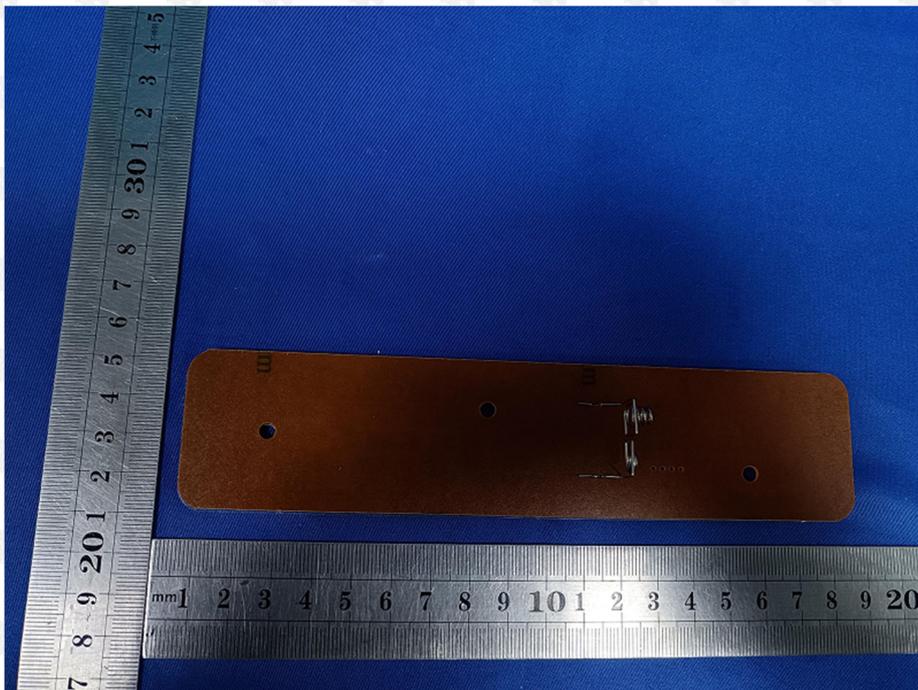
EUT Photo 10



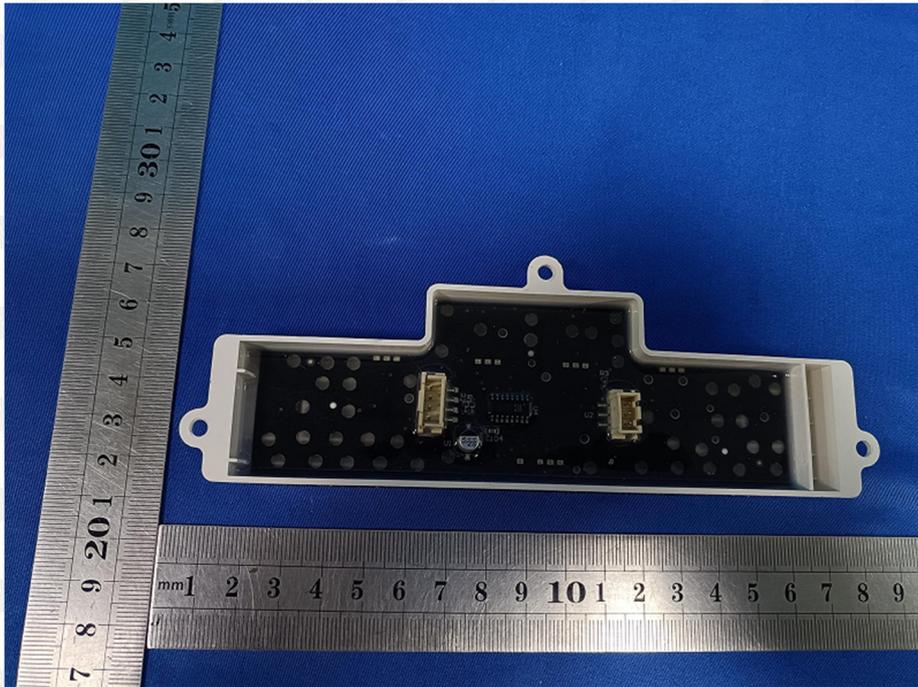
EUT Photo 11



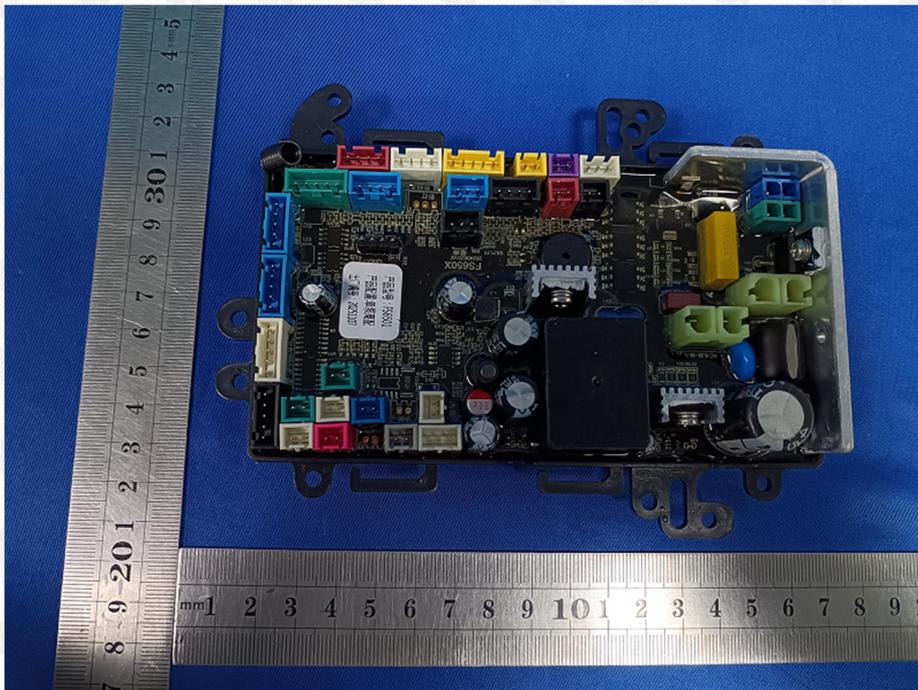
EUT Photo 12



EUT Photo 13



EUT Photo 14



18. EUT TEST SETUP PHOTOGRAPHS

Conducted emissions



Radiated emissions below 1G



H/F



ESD



RS



CS



EFT



Surges



DIPS



***** END OF REPORT *****